Page: 1 of 40

EMC TEST REPORT

Reference No. : WT11095296-S-E-O

Applicant : GlobTek, Inc.

Address : 186 Veterans Dr. Northvale, NJ 07647 USA.

Equipment Under Test (EUT):

Product Name : Switching-Mode Power Supply

Model No : GT-43005-1005 -W2Z-USB (more details refer to 3.3)

Standards : EN 55022: 2006 +A1: 2007

EN 55024: 1998+A1: 2001+A2: 2003 EN 61000-3-2: 2006+A1:2009+A2:2009

EN 61000-3-3: 2008

Date of Test: October 8~10, 2011

Project Engineer : Andy wu

Reviewed By : Philo.Zhong

Test Result : PASS *

Prepared By:

Waltek Services (Shenzhen) Co., Ltd.

1/F, Fukangtai Building, West Baima Rd., Songgang Street, Baoan District, Shenzhen 518105, China

Tel:+86-755-27553488 Fax:+86-755-27553868

* The sample detailed above has been tested to the requirements of Council Directives 2004/108/EC. The test results have been reviewed against the Directives above and found to meet their essential requirements.

The results shown in this test report refer only to the sample(s) tested, This Test report cannot be reproduced, except in full, without prior written permission of the Company

WALTEK SERVICES

1 Test Summary

Test	Test Requirement	Test Method	Class / Severity	Result	
Mains Terminal Disturbance	EN 55022:2006	EN 55022:2006	Class B	PASS	
Voltage, 150kHz to 30MHz	+A1:2007	+A1:2007	Class B	CASS	
Radiation Emission, 30MHz	EN 55022:2006	EN 55022:2006	Class B	PASS	
to 1000MHz	+A1:2007	+A1:2007	Class B	PASS	
Harmonic Emission,	EN 61000-3- 2:2006+A1:2009	EN 61000-3- 2:2006+A1:2009	Clause 7 of	N/A	
100Hz to 2kHz	+A2:2009	+A2:2009	EN61000-3-2	1.011	
Flicker Emission on AC	EN 61000-3-3 :2008	EN 61000-3-3 :2008	Clause 5 of EN61000-3-3	PASS	
ESD	EN 55024 : 1998	EN 61000-4-2:2009	Contact	PASS	
ESD	+A1:2001+A2:2003	EN 61000-4-2.2009	Air	TADD	
Radiated Immunity	EN 55024 : 1998	EN 61000-4-3:2006	3V/m, 80%, 1kHz,	PASS	
(80MHz to 1GHz)	+A1:2001+A2:2003	EN 01000-4-3.2000	Amp. Mod.	11100	
Electrical Fast Transients	EN 55024 : 1998	EN 61000-4-4:	AC±1.0kV	PASS	
(EFT) on AC	+A1:2001+A2:2003	2004+A1:2010	DC±0.5kV	TABB	
Surge Immunity on AC	EN 55024 : 1998	EN 61000-4-5:2006	±1kV D.M.†	PASS	
barge initiality of the	+A1:2001+A2:2003	LIV 01000-4-3.2000	±2kV C.M.‡	11100	
Injected Currents on AC,	EN 55024 : 1998	EN61000-4-6:2009	3Vrms(emf), 80%,	PASS	
150kHz to 80MHz	+A1:2001+A2:2003	E1101000-4-0.2009	1kHz Amp. Mod.	TABB	
Power-frequency magnetic	EN 55024 : 1998	EN 61000-4-8:2010	1A/m	PASS	
field	+A1:2001+A2:2003	121 01000-4-0.2010	17VIII	TADD	
Voltage Dips and	EN 55024 : 1998	T	0 % U _T * for 0.5per	D . CC	
Interruptions on AC	+A1:2001+A2:2003	EN 61000-4-11:2004	0 % U _T * for 250per 70 % U _T * for 25per	PASS	

Remark:

A.M. Amplitude Modulation.

P.M. Pulse Modulation.

† D.M. – Differential Mode

• U_T is the nominal supply voltage

The results shown in this test report refer only to the sample(s) tested, This Test report cannot be reproduced, except in full, without prior written permission of the Company

WALTEK SERVICES

2 Contents

6	Photograph (Nelson		Page
1		SUMMARY	
2	CON	TENTS	3
3	GEN	ERAL INFORMATION	5
	3.1 CL	IENT INFORMATION	5
	3.2 GE	NERAL DESCRIPTION OF E.U.T.	5
		TAILS OF E.U.T	
	3.4 DE	SCRIPTION OF SUPPORT UNITS	5
		ANDARDS APPLICABLE FOR TESTING	
		ST FACILITY	
		ST LOCATION	
4	EQUI	PMENT USED DURING TEST	8
5	EMIS	SSION TEST RESULTS	11
	5.1 M	ins Terminals Disturbance Voltage, 150kHz to 30MHz	11
	5.1.1	E.U.T. Operation	
	5.1.2	Conducted Test Setup	11
	5.1.3	Measurement Data.	
	5.1.4	Conducted Emissions Test Data	
	5.1.5	Photograph–Mains Terminal Disturbance Voltage on AC Test Setup	
		diation Emission Data	
	5.2.1	E.U.T. Operation	
	5.2.2	Measurement Uncertainty	
	5.2.3	Radiated Test Setup	
	5.2.4	Spectrum Analyzer Setup	
	5.2.5	Test procedure	
	5.2.6	Corrected Amplitude & Margin Calculation	
	5.2.7 5.2.8	Summary of Test Results	
	5.2.9	Photograph – Radiation Emission Test Setup	
		RMONICS TEST RESULTS	
		CKER TEST	
	5.4.1	E.U.T. Operation	
	5.4.2	Test Setup.	
	5.4.3	Test Data.	
	5.4.4	Photograph- Flicker Test Setup	
6	IMM	UNITY TEST RESULTS	2 4
	6.1 PEI	RFORMANCE CRITERIA DESCRIPTION	24
	6.2 ES	D	24
	6.2.1	E.U.T. Operation	24
	6.2.2	ESD Test Setup	25
	6.2.3	Direct Application Test Results	
	6.2.4	Indirect Application Test Results	25
	6.2.5	Photograph - ESD Test Setup	
		DIATED IMMUNITY	
	6.3.1	E.U.T. Operation	27

The results shown in this test report refer only to the sample(s) tested, This Test report cannot be reproduced, except in full, without prior written permission of the Company

WALTEK SERVICES

Page: 4 of 40

6.3.2	Radiated Immunity Test Setup	27
6.3.3	B Test Results	28
6.3.4	Photograph - Radiated Immunity Test Setup	28
6.4 E	LECTRICAL FAST TRANSIENTS (EFT)	
6.4.	E.U.T. Operation	29
6.4.2		
6.4.5	B Photograph - EFT Test Setup For EUT On AC Cable	30
6.5 S	URGE	31
6.5.	E.U.T. Operation	31
6.5.2	Pest Results	31
6.5.5	B Photograph -Surge Test Setup	32
6.6 C	onducted Immunity 0.15MHz to 80MHz	33
6.6.	E.U.T. Operation	33
6.6.2	Part Results AC mains of EUT	33
6.6.5	Photograph -Conducted Immunity Test Setup On AC Cable	34
6.7 V	OLTAGE DIPS AND INTERRUPTIONS	35
6.7.1	E.U.T. Operation	35
6.7.2	Voltage Dips and Interruptions Test Setup	35
6.7.3	Measurement Data	35
6.7.4	Photograph - Voltage Dips and Interruptions Test Setup	36
7 PHO	OTOGRAPHS - CONSTRUCTIONAL DETAILS	37
7.1 E	UT-Appearance View	37
7.2 E	UT(GT-43005-1005-W2C-USB)-PCB VIEW	38
8 CE	LABEL	40

The results shown in this test report refer only to the sample(s) tested, This Test report cannot be reproduced, except in full, without prior written permission of the Company

WALTEK SERVICES

3 General Information

3.1 Client Information

Applicant: GlobTek, Inc.

Address of Applicant: 186 Veterans Dr. Northvale, NJ 07647 USA.

Manufacturer 1: GlobTek, Inc.

Address of Manufacturer 1: 186 Veterans Dr. Northvale, NJ 07647 USA.

Manufacturer 2: GlobTek (Suzhou) Co., Ltd.

Address of Manufacturer 2: Building 4, No. 76, Jin Ling East Rd., Suzhou Industrial

Park, Suzhou, JiangSu 215021, China.

3.2 General Description of E.U.T.

Product Name: Switching-Mode Power Supply

Model No. : GT-43005-1005 -W2Z-USB (more details refer to 3.3)

Remark: GT-43005-1005 -W2Z-USB are identical in schematic,

structure and critical components except for plug type and output. Therefore, full test items were performed with GT-43005-1005-W2C-USB. The highest frequency of the internal

sources of the EUT is less than 108MHz.

3.3 Details of E.U.T.

General product information:

GT-43005-1005 -W2Z-USB,

"Z" designates type of plug and can be E for European plug, U for British plug, blank for North American, Japan plug, Taiwan plug, C for Chinese plug, A for Australia plug

Model	Input	Output voltage	Output current	
GT-43005-1005- W2C-USB	100-240V~,50-60Hz,0.3A	5Vdc	2.0A	

3.4 Description of Support Units

The EUT has been tested as an independent unit. All the tests were performed in the condition of AC 230V/50Hz.

3.5 Standards Applicable for Testing

The customer requested EMC tests for a Switching-Mode Power Supply. The standards used were EN55022, EN61000-3-2, EN61000-3-3 for emissions & EN55024 for immunity.

The results shown in this test report refer only to the sample(s) tested, This Test report cannot be reproduced, except in full, without prior written permission of the Company

WALTEK SERVICES

Table 1: Tests Carried Out Under EN 55022: 2006+A1:2007

Standard	Status
EN 55022:2006+A1:2007 Radiation Emission, 30MHz to 1000MHz	√
EN 55022:2006+A1:2007 Mains Terminal Disturbance Voltage,150KHz to 30MHz	√

Table 2: Tests Carried Out Under EN 61000-3-2: 2006+A1:2009+A2:2009& EN 61000-3-3: 2008

EN 61000-3-2: 2006+A1:2009+A2:2009	Harmonics Emissions on AC	X
EN 61000-3-3: 2008	Flicker Emissions on AC	$\sqrt{}$

Table 3: Tests Carried Out Under EN 55024:1998+A1:2001+A2: 2003

	Standard	Status
EN 61000-4-2:2009	Electro-static discharge	$\sqrt{}$
EN 61000-4-3:2006	Radio frequency EM fields (80MHz to 1GHz)	√
EN 61000-4-4:2004+A1:2010	Fast transients	√
EN 61000-4-5:2006	Surges	$\sqrt{}$
EN 61000-4-6: 2009	Radio frequency continuous conducted (150kHz to 80MHz)	√
EN 61000-4-8:2010	Power-frequency magnetic field (50Hz)	Х
EN 61000-4-11:2004	Voltage dips & interruptions	$\sqrt{}$

 $[\]sqrt{}$ Indicates that the test is applicable

[×] Indicates that the test is not applicable

3.6 Test Facility

The test facility has a test site registered with the following organizations:

• IC – Registration No.: 7760A

Waltek Services(Shenzhen) Co., Ltd. has been registered and fully described in a report filed with the Industry Canada. The acceptance letter from the Industry Canada is maintained in our files. Registration 7760A, Aug .03, 2010.

• FCC – Registration No.: 880581

Waltek Services(Shenzhen) Co., Ltd. EMC Laboratory has been registered and fully described in a report filed with the (FCC) Federal Communications Commission. The acceptance letter from the FCC is maintained in our files. Registration 880581, May 26, 2011.

3.7 Test Location

All the tests were performed at:-

Waltek Services(Shenzhen) Co., Ltd. at 1/F, Fukangtai Building, West Baima Rd., Songgang Street, Baoan District, Shenzhen, China.

4 Equipment Used during Test

Equipment Name	Model OS	Equipment No	Specification	Cal. Date	Due Date	Cert. No	Uncertainty
EMC Analyzer	Agilent/ E7405A	MY451149 43	9K-26.5GHz	2011-8- 14	2012-8- 14	WWM20100 587	±1dB
Test Receiver	ROHDE&S CHWARZ/ ESPI	101155	9KHz-3GHz	2011-8- 14	2012-8- 14	WWM20100 588	±1dB
Test Receiver	ROHDE&S CHWARZ/ ESCI	100947	9KHz-3GHz	2011-8- 14	2012-8- 14	WWM20100 589	±1dB
Digital Power Analyzer	Em Test AG/Switzerl and/ DPA 500	V07451030 95	Power:2000VA Vol-range:0- 300V Freq_range:10- 80Hz	2011-8- 14	2012-8- 14	WWD20101 078	Voltage distinguish: 0.025% Power:freq distingish: 0.02Hz
Power Source	Em Test AG/Switzerl and/ACS 500	V07451030 96	Vol-range:0- 300V Freq_range:10- 80Hz	2011-8- 14	2012-8- 14	WWD20101 078	Voltage distinguish: 0.025% Power:freq distingish: 0.02Hz
Electrostatic Discharge Simulator	Em Test AG/Switzerl and/ DITO	V07451030 94	Contact discharge: 500V-10KV Air discharge: 500V-16.5KV	2011-8- 14	2012-8- 14	WWM20100 586	7.5A Current Will be changed in Vm=1.5V
RF Generator	TESEQ GmbH/NSG 4070	25781	Fraq-range: 9K-1GHz RF voltage: -60dB to 10dB	2011-8-	2012-8- 14	WWM20100 590	Power_freq distinguish: 0.1Hz Rfeletricity distinguish:0.1dB
ALL Modules Generator	SCHAFFNE R/ 6150	34579	Voltage:200V- 4.4KV Cuttent:100A- 2.2KA	2011-8- 14	2012-8- 14	WWM20100 591	Voltage:±10% Pulse Cuttent:±10%
AC Power Supply	Beijing hengyuan/ DTDGC-4	W2008020	Voltage: 0- 250V Current: 0-20A	2011-8- 14	2012-8- 14	WWM20100 592	ACV:0.06% ACA:0.15%
Trilog Broadband Antenna	SCHWARZ BECK MESS- ELEKTRO NIK/VULB 9163	336	25-3000MHz	2011- 08-14	2012- 08-14	XDdj2009- 2658	±1dB
Two-Line V- Network	ROHDE&S CHWARZ/ ENV216	100115	9KHz-3GHz	2011-8- 14	2012-8- 14	WWC201009 09	±10%

The results shown in this test report refer only to the sample(s) tested, This Test report cannot be reproduced, except in full, without prior written permission of the Company

WALTEK SERVICES

Page:9 of 40

Equipment Name	Model	Equipment No	Specification	Cal. Date	Due Date	Cert. No	Uncertainty
V-LISN	SCHWARZ BECK MESS- ELEKTRO NIK/ NSLK 8128	8128-259	9KHz-3GHz	2011-8- 14	2012-8- 14	WWC201009 03	±10%
Attenuator 6dB	TESEQ GmbH/ ATN6050	25376	Attenuator 6dB	2011-8- 14	2012-8- 14	WWC201009 04	Attenuation:0.2d B
Magnetic Field Probe 100cm ²	Narda safety TEST Solutions/ ELT-400	M-1070	Test freq range: 1-400KHz	2011-8- 14	2012-8- 14	WWD20101 072	1-10 Hz:16.2% 10-120Hz:2.2% 120-400Hz:4.7%
Voltage Probe	SCHWARZ BECK MESS- ELEKTRO NIK/TK 9420	9420-328	9K-30MHz	2011-8-	2012-8-	WWC201009 05	Insertion Loss:<±0.5dB
CDN M-Type	TESEQ GmbH/ CDN M016	25112	Voltage correct factor: 9.5dB	2011-8- 14	2012-8- 14	WWC201009 06	1.5K- 80MHz:±1dB 80-230MHz:-2 +3dB
EM-Clamp	TESEQ GmbH/ KEMZ 801	25453	Freq_range: 0.15-1000MHz	2011-8- 14	2012-8- 14	WWC201009 02	0.3- 400MHz:±4dB Other freq:±5dB
Attenuator		61115-001- 0024	9KHz-30MHz	2011-8- 14	2012-8- 14	WWC201009 10	
Capacitive Coupling Clamp	SCHAFFNE R/ CDN 8014	25311	Max.permissibl e burst voltage:8KV Typical coupling capacitance:10 0pF	2011-8- 14	2012-8- 14	WWC201009 07	Urel:1.5%,k=2
Signal and Data Line Coupling Network	SCHAFFNE R/ CDN 117	25627	1.2/50μS	2011-8- 14	2012-8- 14	WWC201009 08	Urel:1.0%,k-2
Audio Generator	G <u>IIIINSTE</u> <u>K/</u> GAG-809	ЕН831261	Freq range:10Hz- 1MHz Output Resistance: 600Ω	2011-8- 14	2012-8-	WWS201008 45	Freq: ±(3%+1Hz)
Digital Multimeters	FLUKE/15 B	98760784	Voltage: AC/DC 4mV- 1000V Current:	2011-8- 14	2012-8- 14	DBS2010- 736	DCV Urel=0.1% ACV Urel=0.2% DCA Urel=0.2% ACA Urel=0.2%

The results shown in this test report refer only to the sample(s) tested, This Test report cannot be reproduced, except in full, without prior written permission of the Company

WALTEK SERVICES

Equipment Name	Model	Equipment No	Specification	Cal. Date	Due Date	Cert. No	Uncertainty
			AC/DC40mA- 10A Resistor: 400Ω -40MΩ				OHM Urel=0.2% K=2
Digital Multimeters	FLUKE/15 B	98750790	Voltage: AC/DC 4mV- 1000V Current: AC/DC40mA- 10A Resistor: 400Ω-40ΜΩ	2011-8- 14	2012-8- 14	DBS2010- 735	DCV Urel=0.1% ACV Urel=0.2% DCA Urel=0.2% ACA Urel=0.2% OHM Urel=0.2% K=2
Thermo meter	KTJ/TA218 B	TA218B	Temperature Range: -10°C to 60°C Humidity Range: 25%RH to 98%RH	2011-8-	2012-8- 14	RSD2010312	Humidity: U=3%RH(K=2) Temperature: U=1°C(K=2)
Thermo meter	KTJ/TA218 B	TA218B	Temperature Range: -10°C to 60°C Humidity Range: 25%RH to 98%RH	2011-8-	2012-8-	RSD2010312 7	Humidity: U=3%RH(K=2) Temperature: U=1°C(K=2)
Broad-Band Horn Antenna 1-18GHz	SCHWARZ BECK MESS- ELEKTRO NIK/BBHA 9120D	667	1-18GHz	2011-8-	2012-8- 14	2PB1000012 5-0001	f<10GHz: ±1dB 10GHz <f<18gh z: ±1.5dB</f<18gh
Broadband Preamplifier 0.5-18 GHz	SCHWARZ BECK MESS- ELEKTRO NIK/BBV 9718	9718-147	0.5-18GHz	2011-8-	2012-8- 14	2PB1000012 5-0002	±1.2dB
Oscilloscope	TDS3032B	B401960	0-300MHz	2011-8- 14	2012-8- 14	DZ20102315 23988	Vertical deflection: +0.4% Scanning time: +0.3%

The results shown in this test report refer only to the sample(s) tested, This Test report cannot be reproduced, except in full, without prior written permission of the Company

WALTEK SERVICES

5 Emission Test Results

5.1 Mains Terminals Disturbance Voltage, 150kHz to 30MHz

Test Requirement: EN 55022 Class B Test Method: EN 55022 Class B

Test Result: PASS

Frequency Range: 150kHz to 30MHz

Class/Severity: Class B

Detector: Peak for pre-scan (9kHz Resolution Bandwidth)

Quasi-Peak & Average if maximised peak within 6dB of Average

Limit

5.1.1 E.U.T. Operation

Operating Environment:

Temperature: 25.5 °C Humidity: 51 % RH Atmospheric Pressure: 1012 mbar

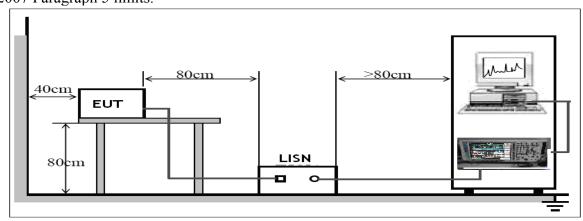
EUT Operation:

Compliance test was performed in full load,half load and no load mode. The full load is the worst,so the test datas only shown the full load mode.

The maximised peak emissions from the EUT was scanned and measured for both the Live and Neutral Lines. Quasi-peak & average measurements were performed if peak emissions were within 6dB of the average limit line.

5.1.2 Conducted Test Setup

The conducted emission tests were performed using the setup accordance with the EN 55022:2006+A1:2007, The specification used in this report was the EN 55022:2006+A1: 2007 Paragraph 5 limits.



The results shown in this test report refer only to the sample(s) tested, This Test report cannot be reproduced, except in full, without prior written permission of the Company

WALTEK SERVICES

5.1.3 Measurement Data

An initial pre-scan was performed on the live and neutral lines.

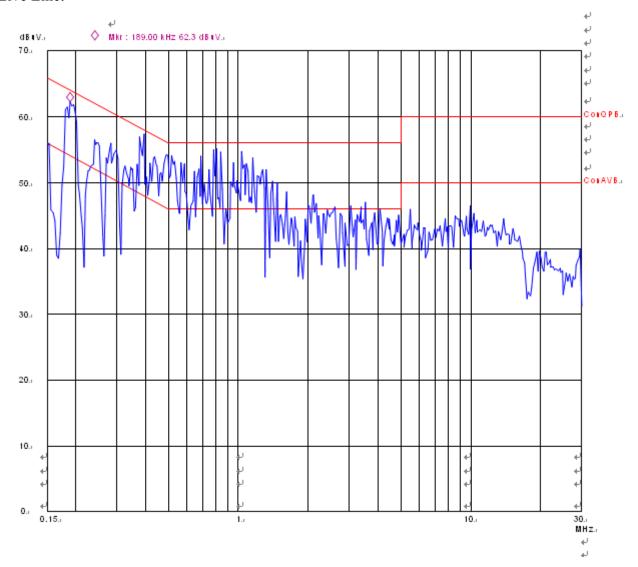
No futher quasi-peak or average measurements were performed since no peak emissions were detected within 10dB line below the average limit.

Please refer to the following peak scan graph for reference.

5.1.4 Conducted Emissions Test Data

Model: GT-43005-1005-W2C-USB

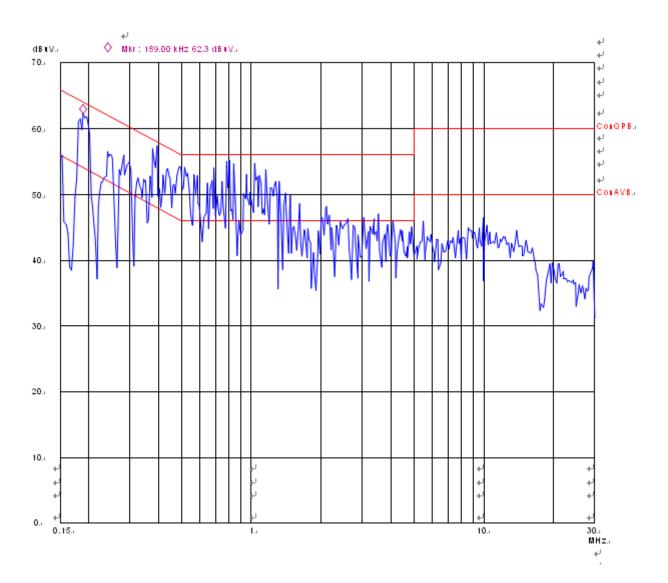
Live Line:



The results shown in this test report refer only to the sample(s) tested, This Test report cannot be reproduced, except in full, without prior written permission of the Company

WALTEK SERVICES

Neutral Line:



The results shown in this test report refer only to the sample(s) tested, This Test report cannot be reproduced, except in full, without prior written permission of the Company

WALTEK SERVICES

Page:14 of 40

Model No.: GT-43005-1005-W2C-USB									
L N									
Frequenc	Quasi-	Peak	Avera	age	Frequenc	Quasi-	Peak	Aver	age
y (MHz)	Readin g dB([V)	Limit dB([V)	Reading dB([V)	Limit dB([V)	y (MHz)	Reading dB([V)	Limit dB([V)	Reading dB([V)	Limit dB([V)
0.183	58.5	64.3	43.7	54.3	0.189	57.2	63.9	42.8	53.9
0.195	57.0	63.8	41.2	53.8	0.240	51.7	62.1	43.7	52.1
0.222	54.0	62.7	41.3	52.7	0.282	51.0	60.8	41.2	50.8
0.270	52.7	61.1	44.1	51.1	0.393	49.5	58.0	40.3	48.0
0.366	48.2	58.6	36.8	48.6	0.805	47.7	56	37.9	46
0.486	50.0	56.2	37.8	46.2	0.840	47.6	56	37.5	46
0.570	47.8	56	35.8	46	1.035	47.8	56	38.0	46
1.075	49.7	56	39.0	46	1.155	47.8	56	36.8	46

The results shown in this test report refer only to the sample(s) tested , This Test report cannot be reproduced, except in full, without prior written permission of the Company WALTEK SERVICES

5.1.5 Photograph– Mains Terminal Disturbance Voltage on AC Test Setup



The results shown in this test report refer only to the sample(s) tested, This Test report cannot be reproduced, except in full, without prior written permission of the Company

WALTEK SERVICES

Page: 16 of 40

5.2 Radiation Emission Data

Test Requirement: EN 55022 Class B Test Method: EN 55022 Class B

Test Result: PASS

Frequency Range: 30MHz to 1000MHz

Class/Severity: Class B

Detector: Peak for pre-scan (120KHz Resolution Bandwidth)

Quasi-Peak & Average if maximised peak within 6dB of Average

Limit

5.2.1 E.U.T. Operation

Operating Environment:

Temperature: 25.5 °C Humidity: 51 % RH Atmospheric Pressure: 1012 mbar

EUT Operation:

Compliance test was performed in full load, half load and no load mode. The full load is the worst, so the test datas only shown the full load mode.

5.2.2 Measurement Uncertainty

All measurements involve certain levels of uncertainties, especially in the field of EMC. The factors contributing to uncertainties are spectrum analyzer, cable loss, antenna factor calibration, antenna directivity, antenna factor variation with height, antenna phase center variation, antenna factor frequency interpolation, measurement distance variation, site imperfections, mismatch (average), and system repeatability.

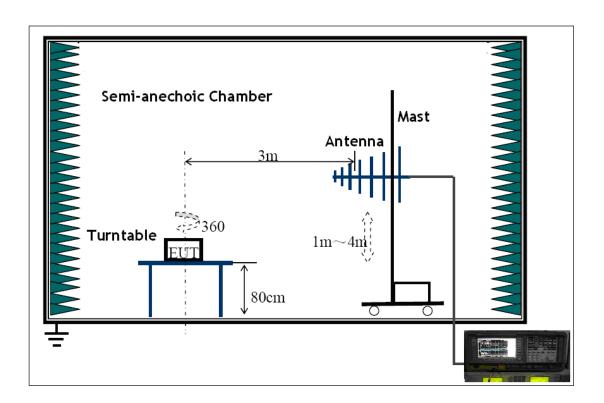
Based on CISPR16-4-2, The Treatment of Uncertainty in EMC Measurements, the best estimate of the uncertainty of a radiation emissions measurement at Waltek EMC Lab is +5.03 dB.

The results shown in this test report refer only to the sample(s) tested, This Test report cannot be reproduced, except in full, without prior written permission of the Company

WALTEK SERVICES

5.2.3 Radiated Test Setup

The radiated emission tests were performed in the 3m Semi- Anechoic Chamber test site, using the setup accordance with the EN 55022:2006+A1:2007, The specification used in this report was the EN 55022:2006+A1:2007 Paragraph 6 limits.



5.2.4 Spectrum Analyzer Setup

According to EN55022 Class B Rules, the system was tested to 1000 MHz.

Start Frequency	30 MHz
Stop Frequency	1000 MHz
Sweep Speed Auto	
IF Bandwidth	120KHz
Video Bandwidth	100KHz
Quasi-Peak Adapter Bandwidth	120 KHz
Quasi-Peak Adapter Mode	Normal
Resolution Bandwidth	100KHz

The results shown in this test report refer only to the sample(s) tested, This Test report cannot be reproduced, except in full, without prior written permission of the Company

WALTEK SERVICES

Page: 18 of 40

5.2.5 Test procedure

For the radiated emissions test, maximizing procedure was performed on the six (6) highest

emissions to ensure EUT is compliant with all installation combinations.

All data was recorded in the peak detection mode. Quasi-peak readings was performed only when an emission was found to be marginal (within \pm 4 dB μ V of specification limits), and

are distinguished with a "**Qp**" in the data table.

The EUT was under normal mode during the final qualification test and the configuration was

used to represent the worst case results.

5.2.6 Corrected Amplitude & Margin Calculation

The Corrected Amplitude is calculated by adding the Antenna Factor and Cable Factor, and

subtracting the Amplifier Gain from the Amplitude reading. The basic equation is as follows:

Corr. Ampl. = Indicated Reading + Antenna Factor + Cable Factor - Amplifier Gain

The "Margin" column of the following data tables indicates the degree of compliance with

the applicable limit. For example, a margin of -7dB μ V means the emission is 7dB μ V below

the maximum limit for Class B. The equation for margin calculation is as follows:

Margin = Corr. Ampl. – Class B Limit

5.2.7 Summary of Test Results

According to the data in section 5.2.8, the EUT complied with the EN55022 Class B

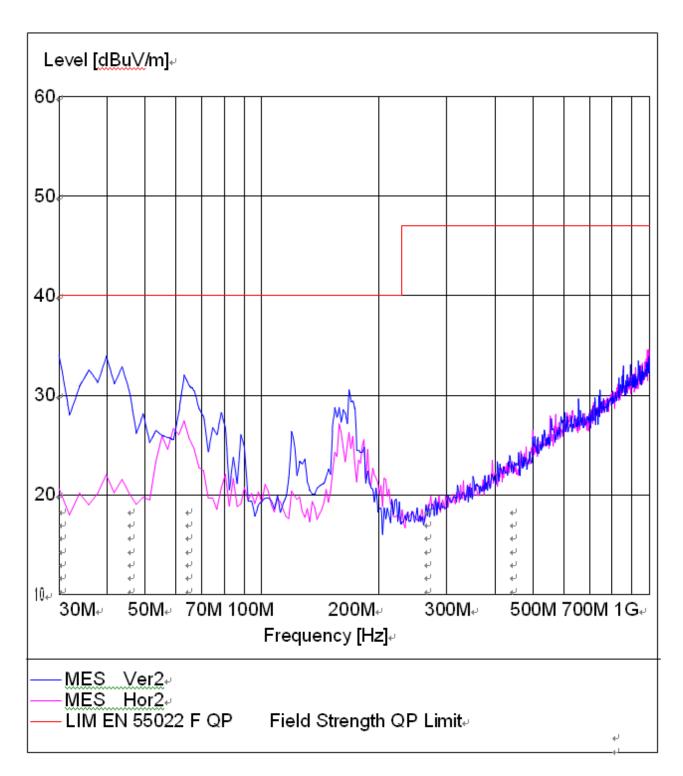
standards.

The results shown in this test report refer only to the sample(s) tested, This Test report cannot be reproduced, except in full, without prior written permission of the Company

WALTEK SERVICES

5.2.8 Radiated Emissions Test Data

Model: GT-43005-1005-W2C-USB



The results shown in this test report refer only to the sample(s) tested, This Test report cannot be reproduced, except in full, without prior written permission of the Company

WALTEK SERVICES

5.2.9 Photograph – Radiation Emission Test Setup



The results shown in this test report refer only to the sample(s) tested, This Test report cannot be reproduced, except in full, without prior written permission of the Company

WALTEK SERVICES

5.3 Harmonics Test Results

Test Requirement: EN61000-3-2 Test Method: EN61000-3-2 Frequency Range: 100Hz to 2kHz

Test Result: N/A

For further details, please refer to Clause 7, Note 1 of EN61000-3-2 which states:-

"For the following categories of equipment limits are not specified in this edition of the standard.

Note 1: Equipment with a rated power of 75W or less, other than lighting equipment."

5.4 Flicker Test

Test Requirement: EN 61000-3-3: 2008 Test Method: EN 61000-3-3: 2008

Test Result PASS

5.4.1 E.U.T. Operation

Operating Environment:

Temperature: 25.5 °C Humidity: 51 % RH Barometric Pressure: 1012 mbar

EUT Operation:

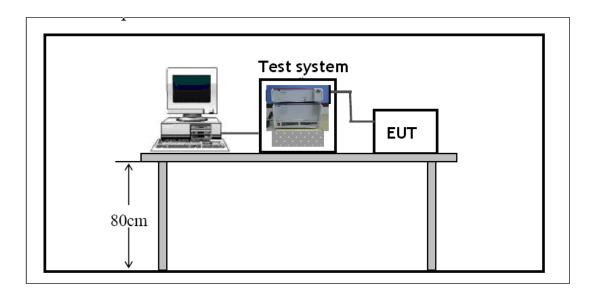
Compliance test was performed in full load mode.

The results shown in this test report refer only to the sample(s) tested, This Test report cannot be reproduced, except in full, without prior written permission of the Company

WALTEK SERVICES

5.4.2 Test Setup

The Flicker Test steup accordance with the EN 61000-3-3, The Specification used in this report was the EN61000-3-3 Paragraph 5 limits.



TEST ITEM	LIMIT	NOTE
Pst	1.0	Pst means short-term flicker indicator.
Plt	0.65	Plt means long-term flicker indicator.
d(t) (%)	3.3	d(t) means maximum time that not exceeds 500 ms.
dmax (%)	4	dmax means maximum relative voltage change.
dc (%)	3.3 dc means relative steady-state volta change	

The results shown in this test report refer only to the sample(s) tested, This Test report cannot be reproduced, except in full, without prior written permission of the Company

WALTEK SERVICES

5.4.3 Test Data

Limit Model	Pst(1.00)	Plt(0.65)	dc [%](3.30)	dmax [%](4.00)	dt [s](0.50)
GT-43005-1005-W2C- USB	0.064	0.028	0.010	0.000	0.000

5.4.4 Photograph- Flicker Test Setup



The results shown in this test report refer only to the sample(s) tested, This Test report cannot be reproduced, except in full, without prior written permission of the Company

WALTEK SERVICES

6 Immunity Test Results

6.1 Performance Criteria Description

Criterion A: The apparatus shall continue to operate as intended. No degradation of

performance or loss of function is allowed below a performance level specified by

the manufacturer, when the apparatus is used as intended.

Criterion B: The apparatus shall continue to operate as intended after the test. No degradation

of performance or loss of function is allowed below a performance level specified

by the manufacturer, when the apparatus is used as intended.

Criterion C: Temporary loss of function is allowed, provided the function is self recoverable or

can be restored by the operation of the controls.

For further details, please refer to EN55024.

6.2 ESD

Test Requirement: EN55024 Test Method: EN61000-4-2

Test Result: PASS

Discharge Impedance: $330 \Omega / 150 pF$

Discharge Voltage: Air Discharge: +/- 8 kV

Contact Discharge: +/- 4 kV HCP & VCP: +/- 4 kV

Polarity: Positive & Negative

Number of Discharge: Minimum 10 times at each test point

Discharge Mode: Single Discharge Discharge Period: 1 second minimum

6.2.1 E.U.T. Operation

Operating Environment:

Temperature: 25.5 °C Humidity: 51 % RH Barometric Pressure: 1012 mbar

EUT Operation:

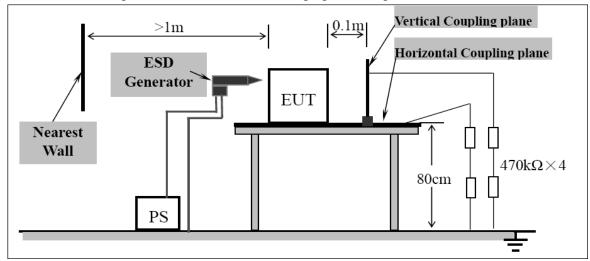
Compliance test was performed in full load mode.

The results shown in this test report refer only to the sample(s) tested, This Test report cannot be reproduced, except in full, without prior written permission of the Company

WALTEK SERVICES

6.2.2 ESD Test Setup

The ESD Test steup accordance with the EN 61000-4-2, The Specification used in this report was the EN 55024 Paragraph 4.2 requirements.



6.2.3 Direct Application Test Results

Observations: Test points: 1. All Exposed Surface & Seams;

2. All metallic part

Direct	Application	Test Re	sults	
Discharge Level (kV)	Polarity (+/-)	Test Point	Contact Discharge	Air Discharge
8	+/-	1	N/A	В
4	+/-	2	В	N/A

Results

B: Degradation in the performance of the E.U.T. was observed.

N/A: Not applicable.

6.2.4 Indirect Application Test Results

Observations: Test points: 1. All sides.

Indirect	Application	Test Re	sults	
Discharge Level (kV) Polarity (+/-) Test Point		Horizontal Coupling Vertical Cou		
4	+/-	1	В	В

Results

B: Degradation in the performance of the E.U.T. was observed.

The results shown in this test report refer only to the sample(s) tested, This Test report cannot be reproduced, except in full, without prior written permission of the Company

WALTEK SERVICES

6.2.5 Photograph - ESD Test Setup



The results shown in this test report refer only to the sample(s) tested , This Test report cannot be reproduced, except in full, without prior written permission of the Company WALTEK SERVICES

6.3 Radiated Immunity

Test Requirement: EN55024
Test Method: EN61000-4-3
Frequency Range: 80MHz–1GHz

Face Under Test: Three Mutually Orthogonal Faces

Severity: 3V/m, 1kHz, 80% Amp. Mod. from 80MHz to 1GHz

Test Result: PASS

6.3.1 E.U.T. Operation

Operating Environment:

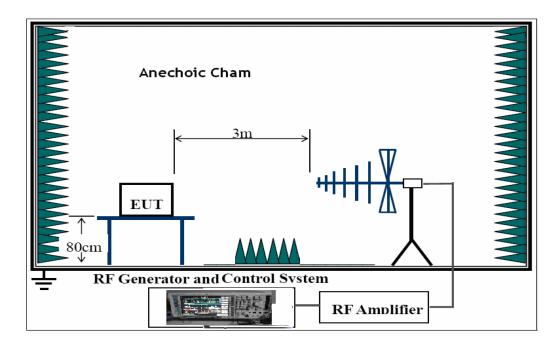
Temperature: 25.5° C Humidity: 51 % RH Barometric Pressure: 1012 mbar

EUT Operation:

Compliance test was performed in full load mode.

6.3.2 Radiated Immunity Test Setup

The Radiated Immunity test setup accordance with the EN 61000-4-3, The Specification used in this report was the EN 55024 Paragraph 4.2.3 requirements.



The results shown in this test report refer only to the sample(s) tested, This Test report cannot be reproduced, except in full, without prior written permission of the Company

WALTEK SERVICES

6.3.3 Test Results

Frequency	Level	Modulation	Position	Result	Observations
80MHz-	1kHz, 80%,	Front	Pass	During test and after	
		Right	Pass		
1GHz	1 3 V/m 1	Amp. Mod.	Rear	Pass	test, the EUT was normal(A).
		Left	Pass		

6.3.4 Photograph - Radiated Immunity Test Setup



The results shown in this test report refer only to the sample(s) tested, This Test report cannot be reproduced, except in full, without prior written permission of the Company

WALTEK SERVICES

6.4 Electrical Fast Transients (EFT)

Test Requirement: EN 55024 Test Method: EN 61000-4-4

Test Result: PASS

Test Level: 1.0kV on AC

Polarity: Positive & Negative

Repetition Frequency: 5kHz Burst Duration: 300ms

Test Duration: 2 minutes per level & polarity

6.4.1 E.U.T. Operation

Operating Environment:

Temperature: 25.5 °C Humidity: 51 % RH Barometric Pressure: 1012 mbar

EUT Operation:

Compliance test was performed in full load mode.

6.4.2 Test Results On AC Cable

Lead under Test	Level (±kV)	Coupling Direct/Clamp	EUT operating mode	Observations (Performance Criterion)
L	±1.0			В
N	±1.0	Direct	t full load	В
L-N	±1.0			В

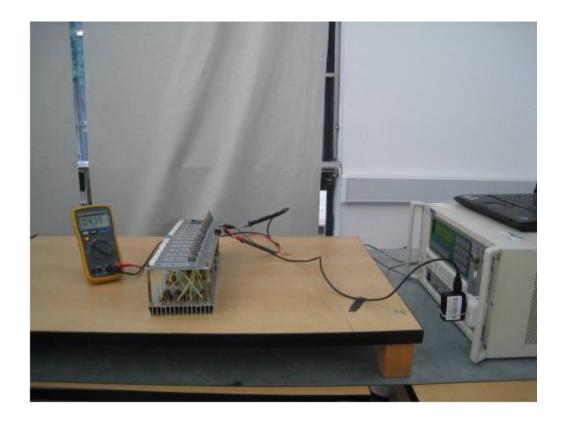
Results

B: Degradation in the performance of the E.U.T. was observed.

The results shown in this test report refer only to the sample(s) tested, This Test report cannot be reproduced, except in full, without prior written permission of the Company

WALTEK SERVICES

6.4.3 Photograph - EFT Test Setup For EUT On AC Cable



The results shown in this test report refer only to the sample(s) tested , This Test report cannot be reproduced, except in full, without prior written permission of the Company

WALTEK SERVICES

6.5 Surge

Test Requirement: EN 55024 Test Method: EN 61000-4-5

Test Result: PASS

Test level: ±1kV Live to Neutral Interval: 60s between each surge

No. of surges: 5 positive, 5 negative at 0° , 90° , 180° , 270° .

6.5.1 E.U.T. Operation

Operating Environment:

Temperature: 25.5 °C Humidity: 51 % RH Barometric Pressure: 1012 mbar

EUT Operation:

Compliance test was performed in full load mode.

6.5.2 Test Results

Level	Voltage	Poll	Path	Pass	Fail
1	0.5kV	±	L-N	/	/
2	1kV	±	L-N	В	/
3	2kV	±	L-PE, N-PE	/	/
4	4kV	±	L-N, L-PE, N-PE	/	/

Results

B: Degradation in the performance of the E.U.T. was observed.

The results shown in this test report refer only to the sample(s) tested, This Test report cannot be reproduced, except in full, without prior written permission of the Company

WALTEK SERVICES

6.5.3 Photograph -Surge Test Setup



The results shown in this test report refer only to the sample(s) tested , This Test report cannot be reproduced, except in full, without prior written permission of the Company WALTEK SERVICES

6.6 Conducted Immunity 0.15MHz to 80MHz

Test Requirement: EN 55024 Test Method: EN 61000-4-6

Test Result: PASS

Frequency Range: 0.15MHz to 80MHz

Test level: 3V rms (unmodulated emf into 150 Ω) Modulation: 80%, 1kHz Amplitude Modulation.

6.6.1 E.U.T. Operation

Operating Environment:

Temperature: 25.5° C Humidity: 51% RH Barometric Pressure: 1012 mbar

EUT Operation:

Compliance test was performed in full load mode.

6.6.2 Test Results AC mains of EUT

Frequency	Line	Test Level	Modulation	Step Size	Dwell Time	Observation (Performance Criterion)
150kHz to 80MHz	2Wire AC Supply Cable	3Vrms	80%, 1kHz Amp. Mod.	1%	1s	During test and after test,EUT was normal (A).

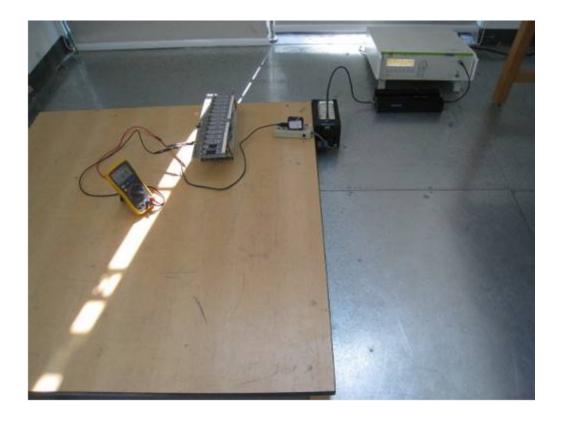
Results

A: No degradation in the performance of the E.U.T. was observed.

The results shown in this test report refer only to the sample(s) tested, This Test report cannot be reproduced, except in full, without prior written permission of the Company

WALTEK SERVICES

6.6.3 Photograph -Conducted Immunity Test Setup On AC Cable



The results shown in this test report refer only to the sample(s) tested, This Test report cannot be reproduced, except in full, without prior written permission of the Company

WALTEK SERVICES

Page:35 of 40

6.7 Voltage Dips and Interruptions

Test Requirement: EN 55024 Test Method: EN 61000-4-11

Test Result: PASS

Test Level(Voltage reduction): 0% & 0% & 70 % of U_T (Supply Voltage)

No. of Dips / Interruptions: 1 per Level at 20ms intervals

6.7.1 E.U.T. Operation

Operating Environment:

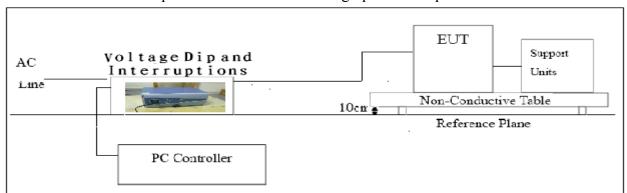
Temperature: 25.5 °C Humidity: 51% RH Barometric Pressure: 1012 mbar

EUT Operation:

Compliance test was performed in full load mode.

6.7.2 Voltage Dips and Interruptions Test Setup

The Voltage dips and Interruptions Test setup accordance with the EN 61000-4-11, the Specification used in this report was the EN 55024 Paragraph 4.2.6 requirements.



6.7.3 Measurement Data

EUT operating mode	Dropout % U _T	Phase	Duration of dropout in Periods	No of dropout	Time between dropout	Observations (Performance Criterion)
full load	95	0°	0.5	3	10ms	В
ditto	95	0°	250	3	5000ms	С
ditto	30	0°	25	3	500ms	С

Results

B: During test, This was within the minimum performance criteria set by the applicant. Please refer to section 6.1 of this report for further details.

The results shown in this test report refer only to the sample(s) tested, This Test report cannot be reproduced, except in full, without prior written permission of the Company

WALTEK SERVICES

6.7.4 Photograph - Voltage Dips and Interruptions Test Setup

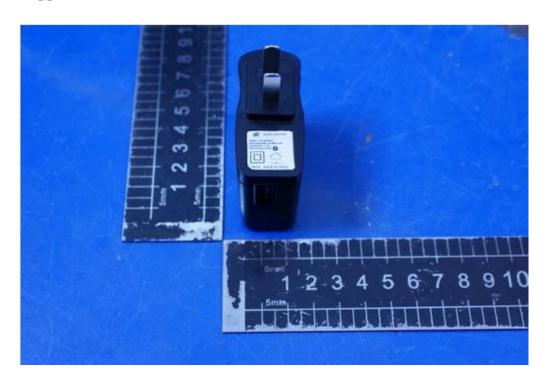


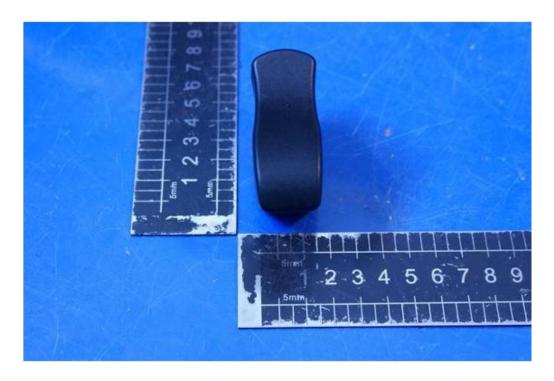
The results shown in this test report refer only to the sample(s) tested, This Test report cannot be reproduced, except in full, without prior written permission of the Company

WALTEK SERVICES

7 Photographs - Constructional Details

7.1 EUT-Appearance View



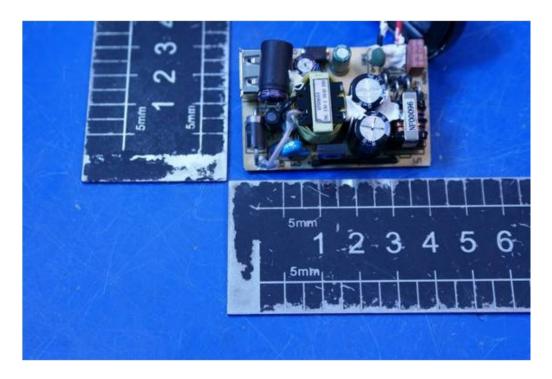


The results shown in this test report refer only to the sample(s) tested, This Test report cannot be reproduced, except in full, without prior written permission of the Company

WALTEK SERVICES

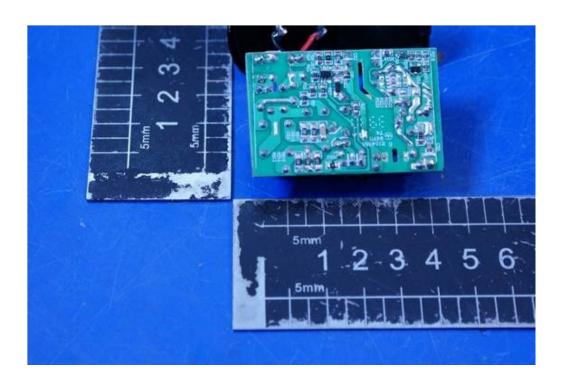
7.2 EUT(GT-43005-1005-W2C-USB)-PCB View





The results shown in this test report refer only to the sample(s) tested, This Test report cannot be reproduced, except in full, without prior written permission of the Company

WALTEK SERVICES

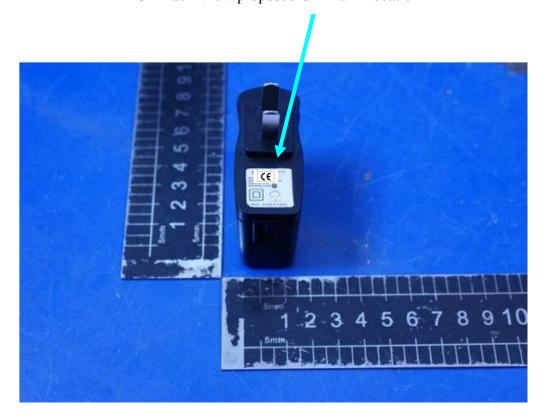


The results shown in this test report refer only to the sample(s) tested , This Test report cannot be reproduced, except in full, without prior written permission of the Company WALTEK SERVICES

8 CE Label

- 1. The CE conformity marking must consist of the initials 'CE' taking the following form: If the CE marking is reduced or enlarged, the proportions given in the above graduated drawing must be respected.
- 2. The CE marking must have a height of at least 5 mm except where this is not possible on account of the nature of the apparatus.
- 3. The CE marking must be affixed to the product or to its data plate. Additionally it must be affixed to the packaging, if any, and to the accompanying documents.
- 4. The CE marking must be affixed visibly, legibly and indelibly. It must have the same height as the initials 'CE'

Proposed Label Location on EUT
EUT Back View/proposed CE Mark Location



The results shown in this test report refer only to the sample(s) tested, This Test report cannot be reproduced, except in full, without prior written permission of the Company

WALTEK SERVICES